
**Metallic materials — Dynamic force
calibration for uniaxial fatigue testing —**

**Part 1:
Testing systems**

*Matériaux métalliques — Étalonnage de la force dynamique uniaxiale
pour les essais de fatigue —*

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ISO copyright office
Case postale 56 • CH-1211 Geneva 20
Tel. + 41 22 749 01 11
Fax + 41 22 749 09 47
E-mail copyright@iso.org
Web www.iso.org

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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

International Standards are drafted in accordance with the rules given in the ISO/IEC Directives, Part 2.

The main task of technical committees is to prepare International Standards. Draft International Standards adopted by the technical committees are circulated to the member bodies for voting. Publication as an International Standard requires approval by at least 75 % of the member bodies casting a vote.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights.

ISO 4965-1 was prepared by Technical Committee ISO/TC 164, *Mechanical testing of metals*, Subcommittee SC 5, *Fatigue testing*.

This first edition of ISO 4965-1, together with ISO 4965-2, cancels and replaces ISO 4965:1979, which has been technically revised.

ISO 4965 consists of the following parts, under the general title *Metallic materials — Dynamic force calibration for uniaxial fatigue testing*:

- *Part 1: Testing systems* (<https://standards.iteh.ai>)
- *Part 2: Dynamic calibration device (DCD) instrumentation*

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Introduction

In a dynamic test, the force experienced by the test-piece (F_t) might differ significantly from the force indicated by the testing system (F_i). The dynamic errors result from inertial forces acting on the force transducer and any dynamic errors in the electronics of the force indicating system. Inertial forces equate to the grip mass (interposed between the force transducer and the test-piece) multiplied by its local acceleration, and therefore depend on

- a) the amplitude of motion
- b) the frequency of motion, and
- c) the grip mass.

The amplitude of motion will, in turn, depend on the applied force and the mechanical configuration of the testing system, including the compliances of the load train, the test-piece, the reaction frame, and the base mounting. For a given frequency and over a given force range, different combinations of compliance values will result in different amplitudes of motion [the motion of a grip holding a very compliant test-piece may even be in the opposite direction (anti-phase) to that of the same grip holding a much stiffer test-piece].

For the purpose of this part of ISO 4965, there must be a linear relationship between the applied force and the displacement of the actuator. Using Method A and the calculated correction factor, the force measurement system will be dynamically calibrated to within 1 % of the applied force range. Using Method B and two dynamic calibration devices (DCDs) of different compliance, the force measurement system will be dynamically calibrated to within 1 % of the applied force range, if the actual test-piece has a compliance between those of the two DCDs.

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Method A (Replica test-piece method) – This method is used for calibrating a dynamic testing system with a DCD, allowing errors of up to 10 % in the indicated force range to be corrected for, using a generated correction factor. The DCD must have the same compliance and mass as the specimens to be tested and the entire load train must be the same as that to be used for the actual testing. Before commencing a new series of dynamic tests, the correction factor relating the indicated force range (ΔF_i) to the test-piece force range (ΔF_t) can be determined using a strain gauged replica test-piece. This factor can be applied either as a correction to the results or to modify the force applied by the testing system, reducing the dynamic force error to less than 1 %. This correction factor is dependent on test frequency, and therefore will have to be determined over the entire range of anticipated test frequencies.

<http://www.iteh-standards.com/iso/61d0e032-4acd-4f76-8c36-5c66a4c9101c/iso-4965-1-2012>

Method B (Compliance envelope method) – This method is used to calibrate a dynamic testing system for use with varying test-piece configuration, using two DCDs of different compliance. The low compliance DCD should have a compliance lower than that of any test-piece to be tested, and the high compliance DCD should have a compliance above that of any test-piece. An operating envelope of test-piece compliance versus frequency can be established for the testing system, within which dynamic errors are maintained to within 1 % of the applied force range. It is assumed that the compliance of the load train is insignificant when compared with the compliance of either DCD. If this is not the case, and the machine is to be used with varying load train compliance values, additional calibration runs will need to be performed.

Metallic materials — Dynamic force calibration for uniaxial fatigue testing —

Part 1: Testing systems

1 Scope

This part of ISO 4965 describes two methods (see Introduction) for determining the relationship between the dynamic force range (ΔF_t) applied to a test-piece in a uniaxial, sinusoidal, constant amplitude test and the force range indicated (ΔF_i) by the testing system.

These methods are applicable to dynamic testing systems operating away from system resonant frequencies and are relevant to testing systems where the dynamic force measurement errors are either unknown or where they are expected to exceed 1 % of the applied force range.

The dynamic force measurement errors are determined by comparison of the peak forces indicated by the dynamic testing system with those measured by the strain gauged dynamic calibration device (DCD). This DCD has previously undergone static calibration (see 5.2.1) against the testing system indicator.

For Method A (*Replica test-piece method*), the dynamic calibration is applicable over the validated range of frequencies for that type of test-piece only. A frequency-dependent correction factor is applicable for the correction of dynamic force measurement errors of up to 10 % of dynamic force range. By using such a correction factor, the actual test-specimen dynamic force measurement error will be reduced to less than 1 % of the dynamic force range.

For Method B (*Compliance envelope method*), the dynamic calibration is applicable over the range of test frequencies validated for test-pieces whose compliance lies between those of the two DCDs. No correction factor is applicable, as Method B does not permit dynamic force measurement errors above 1 % of the dynamic force range.

NOTE Annex A provides guidance on when the system should be re-calibrated by the methods described in this part of ISO 4965.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 7500-1, *Metallic materials — Verification of static uniaxial testing machines — Part 1: Tension/compression testing machines — Verification and calibration of the force-measuring system*

ISO 4965-2, *Metallic materials — Dynamic force calibration for uniaxial fatigue testing — Part 2: Dynamic calibration device (DCD) instrumentation*

3 Terms, definitions, and symbols

For the purposes of this part of ISO 4965, the terms, definitions, and symbols in ISO 4965-2 and the following apply. Figure 1 gives a schematic diagram of the calibration set-up.

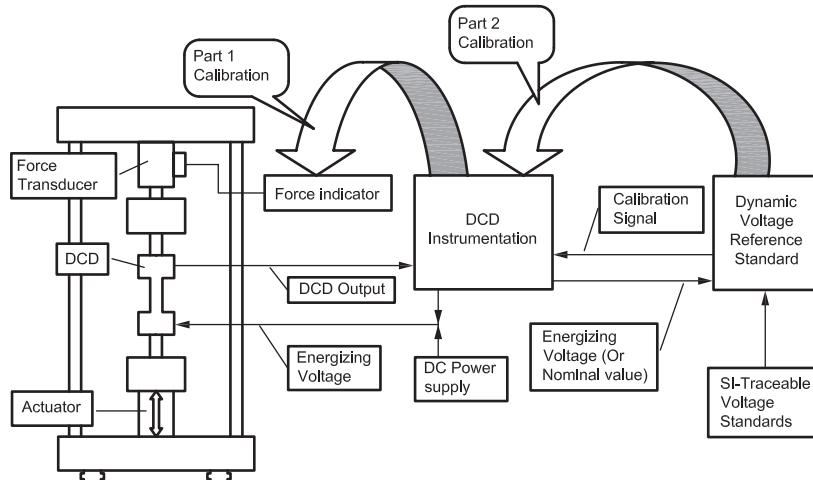


Figure 1 — Schematic diagram of ISO 4965 calibration methodology

3.1 correction factor C

ratio between the dynamic force range determined by a DCD (ΔF_{DCD}) and the dynamic force range indicated by the testing system (ΔF_i), at the same testing frequency

3.2 DCD

dynamic calibration device

strain-gauged replica test-piece (or, for Method B, proving device) that, for Method A, has the same mass and compliance as the specimens to be tested or, for Method B, is of known compliance

3.3 DCD force

[ISO 4965-1:2012](https://standards.iteh.ai/catalog/standards/iso/6610e032-4a/d-4f76-8e36-5e66a4a90fc/iso-4965-1-2012)

F_{DCD} force measured by the DCD, calculated from i_{DCD} after static calibration against the testing system

NOTE See Formulae (2) and (3).

3.4 DCD indication

i_{DCD} output of the DCD instrumentation

NOTE As the DCD instrumentation needs to have previously been calibrated against electrical standards, the DCD indication will be in electrical units, such as mV or mV/V.

3.5 DCD instrumentation

instrumentation used in conjunction with the DCD, including strain gauge bridge output conditioning electronics and display

NOTE The DCD instrumentation may also supply the DCD energising voltage – it could then display the DCD output as an mV/V ratio.

3.6 dynamic force range

ΔF

difference between the maximum (peak) and minimum (valley) values of force under cyclic conditions

3.7**dynamic testing system**

combination of actuator, reaction frame, load train, and instrumentation used to perform cyclic force testing, indicating the applied peak and valley force values

3.8**indicated force** F_i

force measured by the dynamic testing system's statically-calibrated force transducer and indicated by its instrumentation, under both static and dynamic conditions

3.9**indication error** e_i

difference in the force ranges indicated by the testing system instrumentation and the DCD instrumentation, expressed as a percentage of the DCD force range

3.10**load train**

all components, excluding the specimen/DCD, that transmit the force between the actuator and the reaction frame of the dynamic testing system, including the force transducer, adaptors, grips, and other fixtures

4 General requirements

4.1 Temperature

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The ambient temperature at which the dynamic calibration of the uniaxial dynamic testing system is performed shall be recorded. It is recommended that the calibration be performed at a constant ambient temperature, and care should be taken to shield the DCD from draughts and direct sunlight.

4.2 Dynamic testing system

[ISO 4965-1:2012](#)

4.2.1 Static calibration

The dynamic testing system shall have a current certificate of static calibration to ISO 7500-1, Class 1 or better, for the relevant loading conditions.

4.2.2 Calibration frequencies

The dynamic testing system shall be dynamically calibrated over the range of frequencies where dynamic testing is to be performed, with the exception of any test frequencies at which a system resonance affects the force measurement accuracy, as specified in 5.1.1. It is also recommended that, to keep amplitude errors to less than 0,2 %, the maximum test frequency should not exceed 25 % of the testing system instrumentation's bandwidth (see Annex B for two pole filter systems, or 6 % of this bandwidth for single pole filter systems).

Filtering of the measured forces directly affects the dynamic accuracy of these measured forces. Therefore, any filters shall be added before conducting the dynamic calibration. The calibration is only valid with the filters used at the time of calibration.

If Method B is used, the same frequency range shall be used for each of the two DCDs. System resonant frequencies lead to localized areas of increased errors. Care must be taken to identify such areas, with both DCDs, so that actual testing is not performed at frequencies where excessive errors occur.

4.2.3 Dynamic force range

The indicated force end levels used for the dynamic calibration procedure shall lie within the statically calibrated force range of the dynamic testing system, and at the peak values anticipated for the test-piece. The dynamic calibration force range shall also be in between 10 % and 100 % of each DCD's dynamic rating. The

dynamic force range shall be either through-zero, or tension-only, or compression-only. Tension-only dynamic calibrations are not valid in compression and vice versa. Through-zero calibrations verify both tension and compression. This part of ISO 4965 requires that, if a single force range is to be used for dynamic calibration, there is at each test frequency a linear (though potentially different) relationship between applied force and actuator displacement – one way to demonstrate this would be to record and then plot the actuator position as a function of applied force during, or subsequent to, the machine's static force calibration.

NOTE Inertial errors are proportional to acceleration and therefore also to displacement – a linear relationship between force and displacement ensures that inertial errors are proportional to force and thus constant as a proportion of force range, enabling the calibration to be performed over a single force range.

If there is not a linear relationship between applied force and actuator displacement, multiple dynamic force range calibrations are needed before the system is determined to be dynamically calibrated.

The peak and valley values used should be within the working range of the calibration device.

In Method B, the dynamic force ranges used for the two DCDs can be different, but the same frequency range shall be used.

4.2.4 Load train

For Method A, the load train fixtures and fittings employed for the actual dynamic testing shall be used, and the DCD must have the same mass, compliance, and damping as the specimens to be tested (i.e. it should be a standard specimen with strain gauges attached).

For Method B, the calibration shall be performed using a load train with the greatest mass to be used in subsequent testing, as this should maximize the inertial errors generated. A significant change in the compliance of the load train will also affect the dynamic errors generated.

If the machine is to be used to test specimens using load trains of different compliance values (for example, by the insertion of rods for use in a furnace), the followings steps shall be taken.

- Determine the compliance (C_1) of the less compliant DCD (this value should be available from the manufacturer).
- Determine the range of compliances ($\Delta C = C_{\text{maximum}} - C_{\text{minimum}}$) of the load trains to be used (this can be done by actuator displacement measurement at the same force, with the same specimen).
- If $\Delta C > C_1/10$, both DCDs shall be used to calibrate the machine using both the load train of maximum compliance and the load train of minimum compliance.

4.2.5 Mounting of dynamic calibration device (DCD)

The DCD shall be mounted in the load train and attached in the same location as the test-piece would during actual testing.

4.2.6 Dynamic testing system

The dynamic testing system shall be capable of controlling and applying a repeated cyclic force onto the specimen, and providing a read-out of this cyclic force. Typically, a waveform generator either integral to the test system or externally connected to it is used to provide the cyclic waveform of the test. The achieved test force range or end levels are measured and recorded. The dynamic testing system shall be capable of consistently applying repetitive end levels during the entire test. The peak and valley forces as indicated by the dynamic testing system shall repeat within 1 % of the applied force range for every cycle during the entire test. Subclause 5.1.2 specifies the procedure employed to test whether this requirement is met.

4.2.7 DCD instrumentation

The DCD instrumentation shall have been calibrated in accordance with ISO 4965-2. For instrumentation calibrated using a nominal excitation voltage and displaying in voltage units, this value of excitation voltage shall be used during calibration of the testing system. For instrumentation that generates its own excitation